


<b>Search Notes</b> 	<b>Application/Control No.</b> 10501315	<b>Applicant(s)/Patent Under Reexamination</b> TO, BAN CHIN
	<b>Examiner</b> Makiya, David J	<b>Art Unit</b> 2885

### SEARCHED

Class	Subclass	Date	Examiner
362	365	9/25/2007	DJM
362	453	3/20/2008	DJM

### SEARCH NOTES

Search Notes	Date	Examiner
Search in EAST attached	9/25/2007	DJM
362/147,148,150	9/25/2007	DJM
Updated search in EAST attached	3/20/2008	DJM
Inventor name search	3/20/2008	DJM
Assignee search	3/20/2008	DJM
Relevant forward/backward citation search	3/20/2008	DJM
362/147,148,150	3/20/2008	DJM
Updated search in EAST	12/19/2008	DJM
Consulted with Jacob Choi	12/19/2008	DJM
Updated search in EAST	7/16/2009	DJM

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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